

**AN IMPROVED METHOD AND APPARATUS FOR TESTING A COMPUTING
DEVICE WITH MEMORY USING TEST PROGRAM CODE**

ABSTRACT OF THE DISCLOSURE

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10 An apparatus and a method for testing memory of a computing device, and
more specifically to testing a Central Processing Unit (CPU), a system memory, and a
combination thereof. The computing system includes one or more CPUs, a system memory,
input and output devices. Among other features, the apparatus and method described herein
can remove either a defective CPU or a defective portion of system memory from the
computing device. An exemplary apparatus and method also reports to a computer user
whether any CPU or system memory is defective as well as specifically identifying the
defective computing component. The apparatus and method also detects a first defect related
15 to a first corrupted portion of an instruction of a test program code and a second defect
related to a second corrupted portion of the instruction.

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